



NSAI
Standards

Irish Standard
I.S. EN 140401-804:2011

Detail Specification: Fixed low power
film high stability SMD resistors -
Rectangular - Stability classes 0,1; 0,25

I.S. EN 140401-804:2011

Incorporating amendments/corrigenda issued since publication:

EN 140401-804:2011/AC:2011
 EN 140401-804:2011/AC:2012
 EN 140401-804:2011/A1:2013

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<p>NSAI 1 Swift Square, Northwood, Santry Dublin 9</p>	<p>T +353 1 807 3800 F +353 1 807 3838 E standards@nsai.ie W NSAI.ie</p>	<p>Sales: T +353 1 857 6730 F +353 1 857 6729 W standards.ie</p>
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EUROPEAN STANDARD

EN 140401-804/A1

NORME EUROPÉENNE

EUROPÄISCHE NORM

November 2013

ICS 31.040.10

English version

**Detail Specification: Fixed low power film high stability SMD resistors -
Rectangular -
Stability classes 0,1; 0,25**

Spécification particulière: Résistances
fixes à couche de haute stabilité et à
faible dissipation CMS -
Rectangulaires -
Catégories de stabilité 0,1; 0,25

Bauartspezifikation: SMD Schicht-
Festwiderstände niedriger Belastbarkeit
mit hoher Stabilität -
Rechteckig -
Stabilitätsklassen 0,1; 0,25

This amendment A1 modifies the European Standard EN 140401-804:2011; it was approved by CENELEC on 2013-10-14. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this amendment the status of a national standard without any alteration.

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B - 1000 Brussels

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Foreword

This document (EN 140401-804:2011/A1:2013) has been prepared by CLC/TC/40XB "Resistors".

The following dates are fixed:

- latest date by which this document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2014-10-14
- latest date by which the national standards conflicting with this document have to be withdrawn (dow) 2016-10-14

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.



Corrigendum to EN 140401-804

English version

Replace all occurrences of "EN 60115-1:201X" with "EN 60115-1:2011" throughout the text.

In the first table on page 5, replace in the second column, second row, "(month) 201X" with "June 2011".

In 1.3.1, second paragraph, in the brackets, replace "500 k Ω " with "499 k Ω " to read: "1 % > 499 k Ω ".

In Table 3a, third row (RR 1608M), tolerance on rated resistance of ± 1 %, fourth column (Resistance Range), replace "500 k Ω " with "499 k Ω " to read: "24,9 Ω to 499 k Ω ".

In Table 3b, third row (RR 1608M), tolerance on rated resistance of ± 1 %, fourth column (Resistance Range), replace "500 k Ω " with "499 k Ω " to read: "267 k Ω to 499 k Ω ".

In the heading of Table 4, delete "(according to EN 140400:2003, Table 2)" to read: "Table 4 – Temperature coefficients and percentage change of resistance".

In 1.9.4, 7th dash, delete "(only version E)".

January 2012

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Corrigendum to EN 140401-804:2011

English version

Header block

In 2nd row, left field, replace the reference to EN 60115-1:201X by:

EN 60115-1:2011.

In 2nd row, right field, replace the issue date (month) 201X by:

June 2011.

Clause 1.3.1

In 2nd paragraph, 2nd line, replace the resistance value 500 k Ω by:

499 k Ω .

Table 3a

For style RR1608M, tolerance ± 1 %, temperature coefficient ± 25 ppm/K, stability class 0,25, replace the upper resistance range limit 500 k Ω by:

499 k Ω .

Table 3b

For style RR1608M, tolerance ± 1 %, temperature coefficient ± 25 ppm/K, stability class 0,25, replace the upper resistance range limit 500 k Ω by:

499 k Ω .

Table 4

Replace the table title by:

Table 4 – Temperature coefficients and limits of resistance change

Table 7a

In three column headers, replace the reference to EN 60115-1:201X by:

EN 60115-1:2011.

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Table 7b

In four column headers, replace the reference to EN 60115-1:201X by:

EN 60115-1:2011.

Clause 1.9.1

In 3rd paragraph, 2nd line, replace the reference to EN 60115-1:201X, 2.4 by:

EN 60115-1:2011, 2.4.

Clause 1.9.4

Replace the 7th list item by:

- failure rate level;

In the example, last line, replace the reference to EN 60115-1:201X, Annex ZR by:

EN 60115-1:2011, Annex ZR.

Clause 1.10.1

In 1st paragraph, replace the reference to EN 60115-1:201X, 2.7 by:

EN 60115-1:2011, 2.7.

Clause 1.10.9

In 1st paragraph, 2nd line, replace the reference to EN 60115-1:201X, 4.12 by:

EN 60115-1:2011, 4.12.

Clause 2.1.2

In list item 1), 1st line, replace the reference to EN 60115-1:201X, 4.5 by:

EN 60115-1:2011, 4.5.

In list item 2), last line, replace the reference to EN 60115-1:201X, 4.10 by:

EN 60115-1:2011, 4.10.

Clause 2.1.5

Replace the reference to EN 60115-1:201X, Q.1.5 by:

EN 60115-1:2011, Q.1.5

Clause 2.1.6

In 3rd paragraph, replace the reference to EN 60115-1:201X, Annex ZR by:

EN 60115-1:2011, Annex ZR.

I.S. EN 140401-804:2011

Clause 2.2

Replace the reference to EN 60115-1:201X, Q.2.4 by:

EN 60115-1:2011, Q.2.4.

Table A.1

In the row for test 4.6, replace the reference to EN 60115-1:201X, 4.6.1.4 by:

EN 60115-1:2011, 4.6.1.4.

In the row for test 4.7, replace the reference to EN 60115-1:201X, 4.6.1.4 by:

EN 60115-1:2011, 4.6.1.4.

In footnote a, replace the reference to EN 60115-1:201X by:

EN 60115-1:2011.

Table A.2

In the row for test 4.32, replace the reference to EN 60115-1:201X, 4.32.2 b) by:

EN 60115-1:2011, 4.32.2 b).

In both rows for tests 4.18, replace the reference to EN 60115-1:201X, 4.18.2 c) by:

EN 60115-1:2011, 4.18.2 c).

In footnote a, replace the reference to EN 60115-1:201X by:

EN 60115-1:2011.

Annex C

In the entry for EN 60115-1, replace the reference to EN 60115-1:201X by:

EN 60115-1:2011.

Delete the footnote reference 1) and the footnote 1).

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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 140401-804

June 2011

ICS 31.040.10

Supersedes EN 140401-804:2005

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This European Standard was approved by CENELEC on 2011-05-09. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Management Centre: Avenue Marnix 17, B - 1000 Brussels

I.S. EN 140401-804:2011

EN 140401-804:2011

– 2 –

Foreword

This European Standard was prepared by Technical Committee CENELEC TC 40XB, Resistors.

The text of the draft was submitted to the Unique Acceptance Procedure and was approved by CENELEC as EN 140401-804 on 2011-05-09.

This document supersedes EN 140401-804:2005.

Preceding documents on the subject covered by this specification have been:

- only on resistors without established reliability, now version A:
 - CECC 40 401-010:1995-02;
 - CECC 40 401-010:1997-10.

EN 140401-804:2011 the following significant technical changes with respect to EN 140401-804:2005:

- modification of the title;
- introduction of a test on the resistance to electrostatic discharge in 1.6 and Annex A;
- introduction of description and test methods for lead-free soldering in 1.8, 1.10.3 and Annex A;
- introduction of the code letters for temperature coefficient as given in EN 60062;
- revision of the ordering information in 1.9.4;
- revised information on pulse load capability in 1.10.6;
- revised information on resistance value drift in 1.10.7;
- revised information on current noise in 1.10.9;
- adoption of the IECQ rules of procedure, IEC QC 001002-3;
- revision of the sample quantities and the sequence of tests in Annex A.

Additionally, EN 140401-804:2011 is also an editorial revision of EN 140401-804:2005.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2012-05-09
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2014-05-09

This specification is part of four documents describing fixed resistors for surface mount technology as follows:

- | | |
|---------------|---|
| EN 60115-1 | Fixed resistors for use in electronic equipment – Part 1: Generic specification (IEC 60115-1, mod.) |
| EN 140400 | Sectional Specification: Fixed low power surface mount (SMD) resistors |
| EN 140401 | Blank Detail Specification: Fixed low power film surface mount (SMD) resistors |
| EN 140401-804 | Detail Specification: Fixed low power film high stability surface mount (SMD) resistors – Rectangular – Stability classes 0,1; 0,25 |

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